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Final Product/Process Change Notification Document #:FPCN23755XA Issue Date:04 May 2022

Title of Change:	Fabrication Site Transfer from Oudenaarde (Belgium 6") to onsemi Pocatello, Id (USA 8") with Added Passivation, and JCAP Bumping Site Change, with Polyimide Change.	
Proposed First Ship date:	11 Aug 2022 or earlier if approved by customer	
Contact Information:	Contact your local onsemi Sales Office or NoorArdila.Shaharuddin@onsemi.com	
PCN Samples Contact:	Contact your local onsemi Sales Office. Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.	
Additional Reliability Data:	Contact your local onsemi Sales Office or <u>Nicky.Siu@onsemi.com</u>	
Type of Notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. onsemi will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact PCN.Support@onsemi.com	
Marking of Parts/ Traceability of Change:	Affected parts with this change will be identified by the date code	
Change Category:	Assembly Change, Wafer Fab Change	
Change Sub-Category(s):	Manufacturing Site Transfer, Material Change	
Sites Affected:		
onsomi Sitos	External Foundry/Subcan Sites	

onsemi Sites	External Foundry/Subcon Sites
onsemi Pocatello Idaho, United States	JCAP, China

Description and Purpose:

This is the final notification of the wafer fabrication site transfer of the ESD dies from Oudenaarde (Belgium 6") to onsemi Pocatello (USA 8"), and JCET (formerly known as JCAP) new bump site qualification of the CMF dies. The details of the changes are outlined in the tables below.

The transfer of the ESD dies is due to the sale of the Oudenaarde facility and the new JCET site qualification is for products continuance.

Datasheet specifications and product electrical performance remain unchanged.

Transfer of the ESD dies:

	From	То
Fab Site	Wafer manufacturing in Oudenaarde, Belgium	Wafer manufacturing in Pocatello, USA
Wafer size	Wafer diameter 6"	Wafer diameter 8"
Passivation	Wafer without passivation	Wafer with passivation

JCET new bump site qualification for CMF dies:

	From	То
	8" wafers are processed at site B1	8" wafers are processed at site B2
Bumping Site	No.275 Binjiang Road, Jiangyin, Jiangsu, China,	No.78 Changshan Road, Jiangyin, Jiangsu, China, 214433
	214432	
Polymer material	I-8124ER	HD4100

Affected parts with this change will be identified by date code.

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die) : EMI2124MTTAG : S76743 : WDFN-8 <u>Specification</u> JESD22-A108			
: S76743 : WDFN-8 Specification JESD22-A108			
Specification JESD22-A108			
JESD22-A108			
	Condition	Interval	Results
	Ta = 150°C, 100% max rated V	2016 hrs	0/231
JESD22-A103	Ta = 150°C	1008 hrs	0/231
JESD22-A104	Ta = -65°C to +150°C	1000 cyc	0/231
JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/231
JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/231
J-STD-020, JESD22-A113		-	-
JESD22-B106	Ta = 265°C, 10 sec	-	0/30
: EMI4193MTTAG (MY1) : S74552 : WDFN-16, 4x2mm, 0.5P			
Specification	Condition	Interval	Results
JESD22-A108	Ta = 150°C, 100% max rated V	2016 hrs	0/231
JESD22-A103	Ta = 150°C	1008 hrs	0/231
JESD22-A104	Ta = -65°C to +150°C	1000 cycs	0/231
JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/231
JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/231
J-STD-020, JESD22-A113	MSL 1 @ 260°C	-	-
JESD22-B106	Ta = 265°C, 10 sec	-	0/30
E : EMI4193MTTAG (TH3)			
: \$74987			
: WDFN-16, 4x2mm, 0.5P			
Specification	Condition	Interval	Results
JESD22-A108	Ta = 150°C, 100% max rated V	1008 hrs	0/77
	T- 150%	40001	
JESD22-A103	Ta = 150°C	1008 hrs	0/77
JESD22-A103 JESD22-A104	Ta = 150 C Ta = -65°C to +150°C	1008 hrs 1000 cycs	0/77 0/77
JESD22-A104 JESD22-A110	Ta = -65°C to +150°C 130°C, 85% RH, 18.8psig, bias		0/77 0/77
JESD22-A104 JESD22-A110 JESD22-A118	Ta = -65°C to +150°C 130°C, 85% RH, 18.8psig, bias 130°C, 85% RH, 18.8psig, unbiased	1000 cycs	0/77
JESD22-A104 JESD22-A110	Ta = -65°C to +150°C 130°C, 85% RH, 18.8psig, bias	1000 cycs 96 hrs	0/77 0/77
	JESD22-B106 (CMF die) : EMI4193MTTAG (MY1) : S74552 : WDFN-16, 4x2mm, 0.5P Specification JESD22-A108 JESD22-A108 JESD22-A103 JESD22-A104 JESD22-A104 JESD22-A110 JESD22-A118 J-STD-020, JESD22-A113 JESD22-B106 : EMI4193MTTAG (TH3) : S74987 : WDFN-16, 4x2mm, 0.5P Specification	JESD22-B106 Ta = 265°C, 10 sec (CMF die) : : EMI4193MTTAG (MY1) : : S74552 : : WDFN-16, 4x2mm, 0.5P Specification Condition JESD22-A108 Ta = 150°C, 100% max rated V JESD22-A103 Ta = 150°C JESD22-A103 Ta = -65°C to +150°C JESD22-A104 Ta = -65°C to +150°C JESD22-A110 130°C, 85% RH, 18.8psig, bias JESD22-A118 130°C, 85% RH, 18.8psig, unbiased J-STD-020, JESD22-A113 MSL 1 @ 260°C JESD22-B106 Ta = 265°C, 10 sec : EMI4193MTTAG (TH3) : : S74987 : : WDFN-16, 4x2mm, 0.5P Condition	JESD22-B106 Ta = 265°C, 10 sec - (CMF die) : : EMI4193MTTAG (MY1) : S74552 : WDFN-16, 4x2mm, 0.5P - Specification Condition Interval JESD22-A108 Ta = 150°C, 100% max rated V 2016 hrs JESD22-A103 Ta = 150°C 1008 hrs JESD22-A104 Ta = -65°C to +150°C 1000 cycs JESD22-A110 130°C, 85% RH, 18.8psig, bias 96 hrs JESD22-A118 130°C, 85% RH, 18.8psig, unbiased 96 hrs J-STD-020, JESD22-A113 MSL 1 @ 260°C - JESD22-B106 Ta = 265°C, 10 sec - : EMI4193MTTAG (TH3) : : : S74987 : WDFN-16, 4x2mm, 0.5P Specification